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Abstract
The design of thin-film-transistor liquid crystal display (TFT-LCD) integrated circuit (IC) was divided two large sections: low voltage logical circuit and high voltage analog circuit. Of all, the functionalities of possessed many sets of non-linear digital to analog converter (DAC) matrix and polarity inversion could not be used in traditional testing methods. In this thesis, it mainly analyzed the functions, architectures and defects of source driver IC and study the pattern program of source driver IC in the stage of chip probing test. Finally, it implement the our improved pattern program through LCD driver tester. In this article, we discussed every kind of pattern programs such as contact test, high/low power function test, AC timing test, logic output test, IDD test, LCD RON test to talk about the influence of testing time and overkill or underkill. Our proposed pattern program would effectively decreased the wafer testing time and cut down the error appeared of overkill or underkill by our experiment results. And the testing results could be the benefit for foundries to monitor the fabrication and improve the quality. They also can be the reference on improving the design of chip.
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